Approved 11/23/04 ~~[signature]~~

AMENDMENTS TO THE ABSTRACT

Please substitute the following paragraph(s) for the abstract now appearing in the currently filed specification:

The present invention provides a semiconductor test apparatus and method that reduces the number of internal transfers of pattern files to a minimum. In the semiconductor test apparatus and method, a control unit produces a pattern file use frequency table in a pattern file use frequency table memory, and in a set of tests in which a predetermined number of semiconductors to be tested are tested, the use frequency of the pattern files is obtained. The control unit reads out the pattern files based on the frequency of use that has been obtained, and rearranges the pattern files in a memory. In addition, pattern files are deleted in ascending order of the frequency of use when the capacity of the memory becomes insufficient.